

SCANtek⁵

Maximum Productivity

ALTERA M 20.12.10 CMM



REVO[®] -2 head



MODUST[™] software

Advanced 5-axis multi-sensor technology for unrivalled performance

Ten times more productive than its closest rival, LK Metrology's SCANtek5 technology has boosted measurement throughput, shortened production lead times and provided a complete dimensional insight for manufacturers of precision parts and series production.

REVO[®] and MODUST[™] trademarks of Renishaw plc.

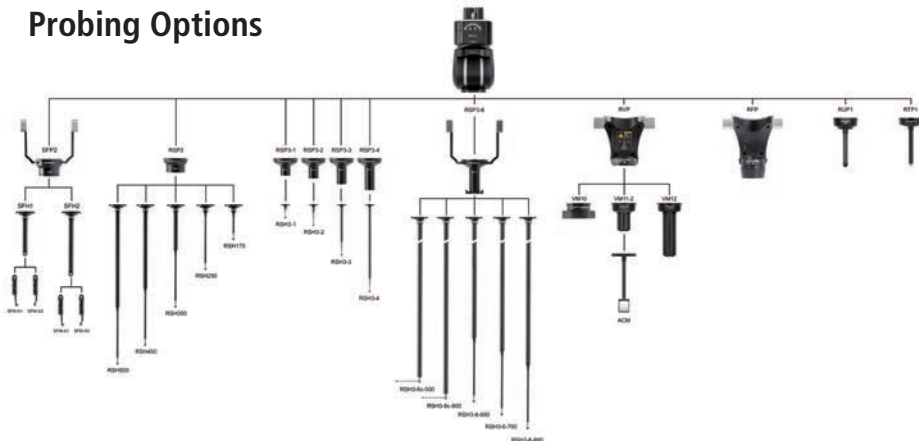
Contact us to book your demonstration

www.LKmetrology.com

Unprecedented measuring speed, the flexibility of multi-sensor technology and optimized 5-axis metrology have boosted measurement throughput, shortened production lead times and provided a more complete awareness of product conformance.

Combining the benefits of ceramic CMM technology and the most advanced 5-axis multi-sensor system, ALTERA SCANTEk provides five interchangeable probe technologies, including tactile scanning, touch-trigger, surface finish, non-contact vision and ultrasonic probes to enable automated selection of the most advantageous probing technology while maximizing the advantages of 5-axis measurement, infinite probe head positioning and long probe assemblies.

Probing Options



Model Sizes

ALTERA ^M						
8.7.6	10.10.8	15.12.10	20.15.10	20.15.12	20.15.15	25.20.15
10.7.6	15.10.8	20.12.10	25.15.10	25.15.12	25.15.15	30.20.15
	20.10.8	25.12.10	30.15.10	30.15.12	30.15.15	35.20.15
	25.10.8	30.12.10	35.15.10	35.15.12	35.15.15	40.20.15
					40.15.15	50.20.15
						60.20.15

(Measure volume = xxxxx00mm)

ALTERA^{SL}

8.7.6	10.10.8	15.12.10	25.15.10	20.15.15	25.20.15
10.7.6	15.10.8	20.12.10		25.15.15	
15.7.6	20.10.8	25.12.10			

(Measure volume = xxx00mm)

Performance

	ALTERA SM	ALTERA ^{SL}
Volumetric Accuracy	from 1.4 μm +L/375	from 1.5 μm +L/400
Repeatability	from 1.4 μm	from 0.7 μm
Probing Accuracy	from 1.2 μm	from 0.9 μm
Scanning Accuracy	from 3,0 μm / 90s	from 3,0 μm / 48s
Velocity	from 830 mm/s	from 850 mm/s
Acceleration	from 2,510 mm/s ²	from 1,400 mm/s ²



LK Metrology's ceramic technology CMM is guaranteed to maintain its original specification for a period of 10 years*

*Conditions apply, see LK Metrology website for full details.



Multi-sensor Inspection

High performance scanning, non-contact inspection and surface finish analysis on a single CMM.



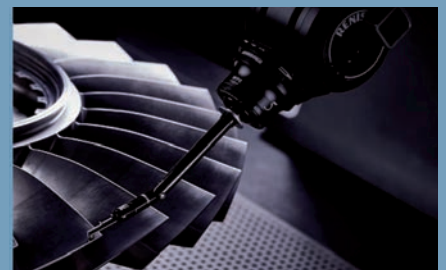
 Ultra Fast Scanning

SCANtek technology allows the stylus to follow a continuous path around complex components without leaving the surface.



 Non-contact Inspection

Measure small and delicate features unsuitable for tactile measurement. Two vision modules provide inspection capability for different applications.



✓ Surface Finish Analysis